

<u>DB Name</u>	<u>Query</u>	<u>Hit Count</u>	<u>Set Name</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	15 and 18	0	<u>L11</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	(minimiz\$3 adj5 discrepancy) and (surface adj profile) nad (approximate adj5 profile adj5 prediction)	0	<u>L10</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	(approximate adj profile adj5 predict\$3) and (tast adj value)	0	<u>L9</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	(test adj5 value) and (test adj5 surface adj profile)	7	<u>L8</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	(test adj5 condition) and (profile adj5 evolution) and (parameter)	0	<u>L7</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	(test adj condition) and (profile adj evolution) and (parameter)	0	<u>L6</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	((process\$3 adj5 simulat\$3) near (calibrat\$3))	24	<u>L5</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	((empirical adj process\$3) near (simulat\$3))	0	<u>L4</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	((semi-empirical adj process\$3) near (simulat\$3))	0	<u>L3</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	((semi adj empirical adj process\$3) near (simulat\$3))	0	<u>L2</u>
USPT,PGPB,JPAB,EPAB,DWPI,TDBD	((semi adj empirical adj process\$3) near (simulat\$3)) and (calibrat\$3)	0	<u>L1</u>

WEST[Generate Collection](#)**Search Results - Record(s) 1 through 20 of 24 returned.**☐ 1. Document ID: US 6230543 B1

L5: Entry 1 of 24

File: USPT

May 15, 2001

US-PAT-NO: 6230543

DOCUMENT-IDENTIFIER: US 6230543 B1

TITLE: Humidity detector calibration method

DATE-ISSUED: May 15, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Froehling; Paul H	Franklin	WI	N/A	N/A
Oman; Gary F	New Berlin	WI	N/A	N/A
Hoefert; Kurt A	Milwaukee	WI	N/A	N/A
Lewis; George	Milwaukee	WI	N/A	N/A
Schultz; Bruce	West Allis	WI	N/A	N/A

US-CL-CURRENT: 73/1_06

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw. Desc	Image
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☐ 2. Document ID: US 6223298 B1

L5: Entry 2 of 24

File: USPT

Apr 24, 2001

US-PAT-NO: 6223298

DOCUMENT-IDENTIFIER: US 6223298 B1

TITLE: Interface for communication with an IC card, and apparatus fitted with such an interface

DATE-ISSUED: April 24, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Tellier; Vincent	Loos	N/A	N/A	FRX
Talaga; Michel	Louvil	N/A	N/A	FRX
Deroo; Daniel	Lesquin	N/A	N/A	FRX

US-CL-CURRENT: 713/501; 710/71, 713/502

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 3. Document ID: US 6212924 B1

L5: Entry 3 of 24

File: USPT

Apr 10, 2001

US-PAT-NO: 6212924

DOCUMENT-IDENTIFIER: US 6212924 B1

TITLE: Process and apparatus for determination of the quality of
a crimped connection

DATE-ISSUED: April 10, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Meisser; Claudio	Cham	N/A	N/A	CHX

US-CL-CURRENT: 72/21.4; 29/705, 29/753, 72/20.2

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 4. Document ID: US 6201401 B1

L5: Entry 4 of 24

File: USPT

Mar 13, 2001

US-PAT-NO: 6201401

DOCUMENT-IDENTIFIER: US 6201401 B1

TITLE: Method for measuring the electrical potential in a
semiconductor element

DATE-ISSUED: March 13, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hellemans; Louis C.	Pellenburg	N/A	N/A	BEX
Trenkler; Thomas	Leuven	N/A	N/A	BEX
De Wolf; Peter	Eeklo	N/A	N/A	BEX
Vandervorst; Wilfried	Mechelen	N/A	N/A	BEX

US-CL-CURRENT: 324/719; 324/753

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 5. Document ID: US 6198300 B1

L5: Entry 5 of 24

File: USPT

Mar 6, 2001

US-PAT-NO: 6198300

DOCUMENT-IDENTIFIER: US 6198300 B1

TITLE: Silicided silicon microtips for scanning probe microscopy

DATE-ISSUED: March 6, 2001

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Doezema; Lambert A.	San Antonio	TX	N/A	N/A
Kaszuba; Philip V.	Essex Junction	VT	N/A	N/A
Moszkowicz; Leon	Stowe	VT	N/A	N/A
Never; James M.	Essex Junction	VT	N/A	N/A
Slinkman; James A.	Montpelier	VT	N/A	N/A

US-CL-CURRENT: 324/762; 324/754

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 6. Document ID: US 6161407 A

L5: Entry 6 of 24

File: USPT

Dec 19, 2000

US-PAT-NO: 6161407

DOCUMENT-IDENTIFIER: US 6161407 A

TITLE: Process and apparatus for determination of the quality of a crimped connection

DATE-ISSUED: December 19, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Meisser; Claudio	Cham	N/A	N/A	CHX

US-CL-CURRENT: 72/21.4; 72/20.1, 72/20.2

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 7. Document ID: US 6139759 A

L5: Entry 7 of 24

File: USPT

Oct 31, 2000

US-PAT-NO: 6139759

DOCUMENT-IDENTIFIER: US 6139759 A

TITLE: Method of manufacturing silicided silicon microtips for scanning probe microscopy

DATE-ISSUED: October 31, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Doezema; Lambert A.	San Antonio	TX	N/A	N/A
Kaszuba; Philip V.	Essex Junction	VT	N/A	N/A
Moszkowicz; Leon	Stowe	VT	N/A	N/A
Never; James M.	Essex Junction	VT	N/A	N/A
Slinkman; James A.	Montpelier	VT	N/A	N/A

US-CL-CURRENT: 216/11; 216/13, 257/10

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 8. Document ID: US 6134511 A

L5: Entry 8 of 24

File: USPT

Oct 17, 2000

US-PAT-NO: 6134511

DOCUMENT-IDENTIFIER: US 6134511 A

TITLE: Method and apparatus for improving building energy simulations

DATE-ISSUED: October 17, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Subbarao; Krishnappa	Golden	CO	80401-5076	N/A

US-CL-CURRENT: 703/6; 703/1

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 9. Document ID: US 6091248 A

L5: Entry 9 of 24

File: USPT

Jul 18, 2000

US-PAT-NO: 6091248

DOCUMENT-IDENTIFIER: US 6091248 A

TITLE: Method for measuring the electrical potential in a semiconductor element

DATE-ISSUED: July 18, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hellemans; Louis C.	Pellenburg	N/A	N/A	BEX
Trenkler; Thomas	Leuven	N/A	N/A	BEX
De Wolf; Peter	Eeklo	N/A	N/A	BEX
Vandervorst; Wilfried	Mechelen	N/A	N/A	BEX

US-CL-CURRENT: 324/719; 250/306, 324/715, 324/724, 324/756

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWC	Draw Desc	Image
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☐ 10. Document ID: US 6080644 A

L5: Entry 10 of 24

File: USPT

Jun 27, 2000

US-PAT-NO: 6080644

DOCUMENT-IDENTIFIER: US 6080644 A

TITLE: Complementary bipolar/CMOS epitaxial structure and process

DATE-ISSUED: June 27, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Drobny; Vladimir F.	Tucson	AZ	N/A	N/A
Bao; Kevin X.	Tucson	AZ	N/A	N/A

US-CL-CURRENT: 438/507; 438/510, 438/607

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWC	Draw Desc	Image
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☐ 11. Document ID: US 5966312 A

L5: Entry 11 of 24

File: USPT

Oct 12, 1999

US-PAT-NO: 5966312
DOCUMENT-IDENTIFIER: US 5966312 A

TITLE: Method for monitoring and analyzing manufacturing processes using statistical simulation with single step feedback

DATE-ISSUED: October 12, 1999

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Chen; Vincent Ming Chun	Milipitas	CA	N/A	N/A

US-CL-CURRENT: 703/6; 700/108

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 12. Document ID: US 5966527 A

L5: Entry 12 of 24 File: USPT Oct 12, 1999

US-PAT-NO: 5966527
DOCUMENT-IDENTIFIER: US 5966527 A

TITLE: Apparatus, article of manufacture, method and system for simulating a mass-produced semiconductor device behavior

DATE-ISSUED: October 12, 1999

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Krivokapic; Zoran	Santa Clara	CA	N/A	N/A
Heavlin; William D.	San Francisco	CA	N/A	N/A

US-CL-CURRENT: 703/14

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 13. Document ID: US 5886909 A

L5: Entry 13 of 24 File: USPT Mar 23, 1999

US-PAT-NO: 5886909

DOCUMENT-IDENTIFIER: US 5886909 A

TITLE: Defect diagnosis using simulation for IC yield improvement

DATE-ISSUED: March 23, 1999

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Milor; Linda	Stanford	CA	N/A	N/A
Peng; Yeng-Kaung	Los Altos	CA	N/A	N/A
Phan; Khoi Anh	San Jose	CA	N/A	N/A
Steele; David	Sunnyvale	CA	N/A	N/A

US-CL-CURRENT: 716/4; 700/110, 700/121

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 14. Document ID: US 5866437 A

L5: Entry 14 of 24

File: USPT

Feb 2, 1999

US-PAT-NO: 5866437

DOCUMENT-IDENTIFIER: US 5866437 A

TITLE: Dynamic process window control using simulated wet data from current and previous layer data

DATE-ISSUED: February 2, 1999

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Chen; Ming Chun	Milpitas	CA	N/A	N/A
Steffan; Paul J.	Elk Grove	CA	N/A	N/A

US-CL-CURRENT: 438/14; 438/15

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 15. Document ID: US 5803570 A

L5: Entry 15 of 24

File: USPT

Sep 8, 1998

US-PAT-NO: 5803570

DOCUMENT-IDENTIFIER: US 5803570 A

TITLE: Calibration system and method for display optical systems

DATE-ISSUED: September 8, 1998

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Chen; Chungte W.	Irvine	CA	N/A	N/A
Zimmerman; James D.	Venice	CA	N/A	N/A
Ansley; David A.	Sterling	VA	N/A	N/A

US-CL-CURRENT: 353/122; 348/745

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 16. Document ID: US 5723981 A

L5: Entry 16 of 24

File: USPT

Mar 3, 1998

US-PAT-NO: 5723981

DOCUMENT-IDENTIFIER: US 5723981 A

TITLE: Method for measuring the electrical potential in a semiconductor element

DATE-ISSUED: March 3, 1998

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hellemans; Louis C.	Pellenburg	N/A	N/A	BEX
Trenkler; Thomas	Leuven	N/A	N/A	BEX
De Wolf; Peter	Eeklo	N/A	N/A	BEX
Vandervorst; Wilfried	Mechelen	N/A	N/A	BEX

US-CL-CURRENT: 324/719; 250/306, 324/715, 324/724, 324/756

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 17. Document ID: US 5719796 A

L5: Entry 17 of 24

File: USPT

Feb 17, 1998

US-PAT-NO: 5719796

DOCUMENT-IDENTIFIER: US 5719796 A

TITLE: System for monitoring and analyzing manufacturing processes using statistical simulation with single step feedback

DATE-ISSUED: February 17, 1998

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Chen; Vincent Ming Chun	Milipitas	CA	N/A	N/A

US-CL-CURRENT: 703/13; 700/108, 700/174, 700/222, 702/181

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 18. Document ID: US 5634585 A

L5: Entry 18 of 24

File: USPT

Jun 3, 1997

US-PAT-NO: 5634585

DOCUMENT-IDENTIFIER: US 5634585 A

TITLE: Method for aligning and assembling spaced components

DATE-ISSUED: June 3, 1997

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Stansbury; Darryl	Boise	ID	N/A	N/A

US-CL-CURRENT: 228/105; 156/64, 228/177, 445/24

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 19. Document ID: US 5241185 A

L5: Entry 19 of 24

File: USPT

Aug 31, 1993

US-PAT-NO: 5241185

DOCUMENT-IDENTIFIER: US 5241185 A

TITLE: Proximity correction method for E-beam lithography

DATE-ISSUED: August 31, 1993

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Meiri; Abraham Z.	Haifa	N/A	N/A	ILX
Ramm; Dov	Menashe	N/A	N/A	ILX

US-CL-CURRENT: 250/492.2

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KMIC	Draw Desc	Image
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☐ 20. Document ID: US 4073304 A

L5: Entry 20 of 24

File: USPT

Feb 14, 1978

US-PAT-NO: 4073304

DOCUMENT-IDENTIFIER: US 4073304 A

TITLE: System for calibrating a pump

DATE-ISSUED: February 14, 1978

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Lerner; Julius	Broomall	PA	N/A	N/A
Iglesias; Edmundo J.	Lindwood	PA	N/A	N/A

US-CL-CURRENT: 137/101.21; 73/1.27, 73/1.31, 73/168

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KMIC	Draw Desc	Image
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Term	Documents
PROCESS\$3	0
PROCESS.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	3002148
PROCESSA.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	75
PROCESSAB.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	7
PROCESSABI.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	6
PROCESSABL.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	3
PROCESSACH.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	1
PROCESSAED.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	1
PROCESSALL.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	22
PROCESSAN.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	2
(((PROCESS\$3 ADJ5 SIMULAT\$3) NEAR (CALIBRAT\$3))) .USPT,PGPB,JPAB,EPAB,DWPI,TDBD.	24

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1. Document ID: US 6151532 A

L8: Entry 1 of 7

File: USPT

Nov 21, 2000

US-PAT-NO: 6151532

DOCUMENT-IDENTIFIER: US 6151532 A

TITLE: Method and apparatus for predicting plasma-process surface profiles

DATE-ISSUED: November 21, 2000

INVENTOR- INFORMATION:

NAME	CITY	STATE	ZIP	CODE	COUNTRY
Barone; Maria E.	Sunnyvale	CA	N/A		N/A
Gottschos; Richard A.	Pleasanton	CA	N/A		N/A
Vahedi; Vahid	Albany	CA	N/A		N/A

US-CL-CURRENT: 700/121; 204/192.13, 204/192.33, 324/460, 324/464,
438/729, 700/108, 700/109, 700/117, 700/123, 700/46, 700/47

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KMC	Draw. Desc	Image
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☐ 2. Document ID: US 6028670 A

L8: Entry 2 of 7

File: USPT

Feb 22, 2000

US-PAT-NO: 6028670

DOCUMENT-IDENTIFIER: US 6028670 A

TITLE: Interferometric methods and systems using low coherence illumination

DATE-ISSUED: February 22, 2000

INVENTOR- INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Deck; Leslie L.	Middletown	CT	N/A	N/A

US-CL-CURRENT: 356/497; 356/357, 356/511

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KMOC	Draw. Desc	Image
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☐ 3. Document ID: US 5953124 A

L8: Entry 3 of 7

File: USPT

Sep 14, 1999

US-PAT-NO: 5953124

DOCUMENT-IDENTIFIER: US 5953124 A

TITLE: Interferometric methods and systems using low coherence illumination

DATE-ISSUED: September 14, 1999

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Deck; Leslie L.	Middletown	CT	N/A	N/A

US-CL-CURRENT: 356/497; 356/359, 356/511

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 4. Document ID: US 5321497 A

L8: Entry 4 of 7

File: USPT

Jun 14, 1994

US-PAT-NO: 5321497

DOCUMENT-IDENTIFIER: US 5321497 A

TITLE: Interferometric integration technique and apparatus to confine 2.pi. discontinuity

DATE-ISSUED: June 14, 1994

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Ai; Chiayu	Tucson	AZ	N/A	N/A
Xu; Yiping	Tucson	AZ	N/A	N/A

US-CL-CURRENT: 356/514; 356/347, 356/353, 356/360, 382/108, 382/171, 702/108

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Image
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☐ 5. Document ID: US 3795430 A

L8: Entry 5 of 7

File: USPT

Mar 5, 1974

US-PAT-NO: 3795430

DOCUMENT-IDENTIFIER: US 3795430 A

TITLE: WEAR RESISTANT FRICTIONALLY CONTACTING SURFACES

DATE-ISSUED: March 5, 1974

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Farley; Carl Wiern	Hockessin	DE	N/A	N/A

US-CL-CURRENT: 384/625; 420/436, 420/441

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KMIC	Draw Desc	Image
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☐ 6. Document ID: US 3580062 A

L8: Entry 6 of 7

File: USPT

May 25, 1971

US-PAT-NO: 3580062

DOCUMENT-IDENTIFIER: US 3580062 A

TITLE: SURFACE-MEASURING DEVICE

DATE-ISSUED: May 25, 1971

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Perthen; Johannes	Hannover	N/A	N/A	DT
Gerighausen; Werner	Ronnenberg	N/A	N/A	DT
Kunzmann; Konrad	Rollinghausen	N/A	N/A	DT
Dreyer; Heinz	Devese	N/A	N/A	DT

US-CL-CURRENT: 73/105

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KMIC	Draw Desc	Image
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☐ 7. Document ID: EP 1060501 A1, WO 9945567 A1, US 6151532 A

L8: Entry 7 of 7

File: DWPI

Dec 20, 2000

DERWENT-ACC-NO: 1999-551106
DERWENT-WEEK: 200105
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TITLE: Determining a respective process value of at least one input variable governing a plasma process sequence for creating a desired surface profile on a substrate for e.g. plasma deposition or plasma etching

INVENTOR: BARONE, M E; GOTTSCHO, R A ; VAHEDI, V

PRIORITY-DATA: 1998US-0033997 (March 3, 1998)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE	PAGES	MAIN-IPC
EP 1060501 A1	December 20, 2000	E	000	H01J037/32
WO 9945567 A1	September 10, 1999	E	029	H01J037/32
US 6151532 A	November 21, 2000	N/A	000	G06F019/00

INT-CL (IPC): G06F 19/00; H01J 37/32

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWIC	Draw Desc	Clip Img	Image
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Term	Documents
TEST.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	809989
TESTS.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	303647
VALUE.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	1967470
VALUES.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	881728
SURFACE.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	4972287
SURFACES.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	1485668
PROFILE.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	341753
PROFILES.DWPI,TDBD,EPAB,JPAB,USPT,PGPB.	92308
(((TEST ADJ5 SURFACE) ADJ PROFILE) AND (TEST ADJ5 VALUE)).USPT,PGPB,JPAB,EPAB,DWPI,TDBD.	7

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